

**Search Notes**

Application/Control No.

10/694,012

Examiner

Mark A. Chapman

Applicant(s)/Patent under  
Reexamination

NAKANISHI ET AL.

Art Unit

1756

**SEARCHED**

Class	Subclass	Date	Examiner
430	108.7	8/25/2005	MC
	122		
	125		
	137.19		
	137.14		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	8/25/2005	MC